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Application/Control No.	Applicant(s)/Patent under Reexamination
10/706,560	LEE ET AL.
Examiner	Art Unit
Duc M. Nguyen	2685

SEARCHED				
Class	Subclass	Date	Examiner	
455	575.3 569.1 350			
	90.1 90.2			
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379	433.01			
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EAST	2/8/2006	DN
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